

Terrestrial photovoltaic (PV) modules - Design qualification and type approval - Part 2: Test procedures

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English Version

## Terrestrial photovoltaic (PV) modules - Design qualification and type approval - Part 2: Test procedures (IEC 61215-2:2016)

Modules photovoltaïques (PV) pour applications terrestres -  
Qualification de la conception et homologation - Partie 2:  
Procédures d'essai  
(IEC 61215-2:2016)

Terrestrische Photovoltaik (PV) Module - Bauarteignung  
und Bauartzulassung - Teil 2: Prüfverfahren  
(IEC 61215-2:2016)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

## European foreword

The text of document 82/1048/FDIS, future edition 1 of IEC 61215-2, prepared by IEC/TC 82 "Solar photovoltaic energy systems" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61215-2:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-08-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-02-10

This document supersedes EN 61215:2005 (partially).

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## Endorsement notice

The text of the International Standard IEC 61215-2:2016 was approved by CENELEC as a European Standard without any modification.

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cenelec.eu](http://www.cenelec.eu).

<u>Publication</u>	<u>Year series</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year series</u>
IEC 60050		International Electrotechnical Vocabulary	-	
IEC 60068-1	-	Environmental testing -- Part 1: General and guidance	EN 60068-1	-
IEC 60068-2-21	-	Environmental testing -- Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21	-
IEC 60068-2-78	-	Environmental testing -- Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60721-2-1	-	Classification of environmental conditions appearing in nature - Temperature and humidity	EN 60721-2-1	-
IEC 60891	-	Photovoltaic devices - Procedures for temperature and irradiance corrections to measured I-V characteristics	EN 60891	-
IEC 60904-1	-	Photovoltaic devices -- Part 1: Measurement of photovoltaic current-voltage characteristics	EN 60904-1	-
IEC 60904-2	-	Photovoltaic devices - Part 2: Requirements for photovoltaic reference devices	EN 60904-2	-
IEC 60904-3	-	Photovoltaic devices - Part 3: Measurement principles for terrestrial photovoltaic (PV) solar devices with reference spectral irradiance data	EN 60904-3	-
IEC 60904-7	-	Photovoltaic devices -- Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices	EN 60904-7	-
IEC 60904-8	-	Photovoltaic devices -- Part 8: Measurement of spectral response of a photovoltaic (PV) device	EN 60904-8	-
IEC 60904-9	-	Photovoltaic devices -- Part 9: Solar simulator performance requirements	EN 60904-9	-
IEC 60904-10	-	Photovoltaic devices -- Part 10: Methods of linearity measurement	EN 60904-10	-
IEC 61215-1	-	Terrestrial photovoltaic (PV) modules - Design qualification and type approval -- Part 1: Requirements for testing	EN 61215-1	-
IEC 61853-2	-	Photovoltaic (PV) module performance testing and energy rating -- Part 2: Spectral response, incidence angle and module operating temperature measurements	-	-
IEC 62790	-	Junction boxes for photovoltaic modules - Safety requirements and tests	EN 62790	-
ISO 868	-	Plastics and ebonite - Determination of indentation hardness by means of a durometer (Shore hardness)	EN ISO 868	-

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## INTRODUCTION

Whereas Part 1 of this standard series describes requirements (both in general and specific with respect to device technology), the sub-parts of Part 1 define technology variations and Part 2 defines a set of test procedures necessary for design qualification and type approval. The test procedures described in Part 2 are valid for all device technologies.

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